



Welcome to the 36th RD50 Workshop

CERN, online, 3-5.6.2020

- Outline
 - Some recent RD50 news
 - This Workshop





The RD50 Collaboration

- RD50: 63 *institutes and 370 members*

50 European institutes

Austria (HEPHY), Belarus (Minsk), Czech Republic (Prague (3x)),
Finland (Helsinki, Lappeenranta), France (Marseille, Paris, Orsay),
Germany (Bonn, Dortmund, Freiburg, Göttingen, Hamburg (2x),
Karlsruhe, Munich(2x)), Greece (Demokritos), Italy (Bari, Perugia, Pisa,
Trento, Torino), Croatia (Zagreb), Lithuania (Vilnius), Montenegro
(Montenegro), Netherlands (NIKHEF), Poland (Krakow), Romania
(Bucharest), Russia (Moscow, St.Petersburg), Slovenia (Ljubljana),
Spain (Barcelona(3x), Santander, Sevilla (2x), Valencia), Switzerland
(CERN, PSI, Zurich), United Kingdom (Birmingham, Glasgow,
Lancaster, Liverpool, Oxford, Manchester, RAL)



3 new members 2019



Full member list: www.cern.ch/rd50

8 North-American institutes

Canada (Ottawa), USA (BNL, Brown Uni,
Fermilab, LBNL, New Mexico, Santa Cruz,
Syracuse)

1 Middle East institute

Israel (Tel Aviv)

2 Asian institutes

China (Beijing-IHEP, Hefei), India (Delhi)

New members 11/2019



- Carleton University; NRC (National Research Council) Group, **Ottawa, Canada**
 - Team leader: Thomas Koffas
- University of **Montenegro**, Faculty of Sciences and Mathematics,
 - Team Leader: Gordana Lastovicka-Medin
- Department of Modern Physics and State Key Laboratory of Particle Detection and Electronics; University of Science and Technology of China (USTC); **Hefei, P. R. China**
 - Team Leader: Yanwen Liu



RD50 Organizational Structure



Co-Spokespersons

Gianluigi Casse

(Liverpool University, UK
& FBK-CMM, Trento, Italy)

Michael Moll

(CERN EP-DT)

Defect / Material Characterization

Ioana Pintilie
(NIMP Bucharest)

- Characterization of microscopic properties of standard-, defect engineered and new materials; pre- and post- irradiation
- DLTS, TSC,
- SIMS, SR, ...
- NIEL (calculations)
- Cluster and point defects
- Boron related defects
- SiC based detectors

Detector Characterization

Eckhart Fretwurst
(Hamburg University)

- Characterization of test structures (IV, CV, CCE, TCT,..)
- Development and testing of defect engineered devices
- EPI, MCZ and other materials
- NIEL (experimental)
- Device modeling
- Operational conditions
- Common irradiations
- Wafer procurement (M.Moll)
- Acceptor removal (Kramberger)
- TCAD modeling (J.Schwandt)

New Structures

Giulio Pellegrini
(CNM Barcelona)

- 3D detectors
- Thin detectors
- Cost effective solutions
- Other new structures
- Detectors with internal gain
- LGAD:Low Gain Avalanche Det.
- Deep Depleted Avalanche Det.
- Slim Edges
- HVC MOS
- LGAD (S.Hidalgo)
- HVC MOS (E. Vilella)

Full Detector Systems

Gregor Kramberger
(Ljubljana University)

- LHC-like tests
- Links to HEP (LHC P2, FCC)
- Links electronics R&D
- Low rho strips
- Sensor readout (Alibaba)
- Comparison:
 - pad-mini-full detectors
 - different producers
- Radiation Damage in HEP detectors
- Timing detectors
- Test beams (M.Bomben & G.Casse)

Collaboration Board Chair & Deputy: G.Kramberger (Ljubljana) & J.Vaitkus (Vilnius), Conference committee: U.Parzefall (Freiburg)
CERN contact: M.Moll (EP-DT), Secretary: V.Wedlake (EP-DT), Budget holder: M.Moll & M.Glaser (EP-DT) , EXSO: R.Costanzi (EP-DT)

RD50 – 5 Year Work Plan



- **5 year work program submitted in May 2018**

- Approved by CERN Research Board in June 2018

- **Workplan [70 milestones]**

- **Defect and Material Characterization [16 MS]**

- p-type silicon [7 MS]
- Cluster defects [4 MS]
- Theory of defects [5 MS]

- **Device Characterization & Device Simulation [21MS]**

- Silicon materials [5 MS]
- Extreme fluences [5 MS]
- Experimental techniques [3 MS]
- Surface damage [1 MS]
- TCAD simulations [7 MS]

- **New structures [21 MS]**

- 3D sensors [6 MS] ; LGAD [4 MS]
- CMOS [6 MS] ; New Materials [5 MS]

- **Full Detector Systems [12 MS]**

- LHC [7 MS]; HL-LHC [3 MS]
- FCC [2 MS]

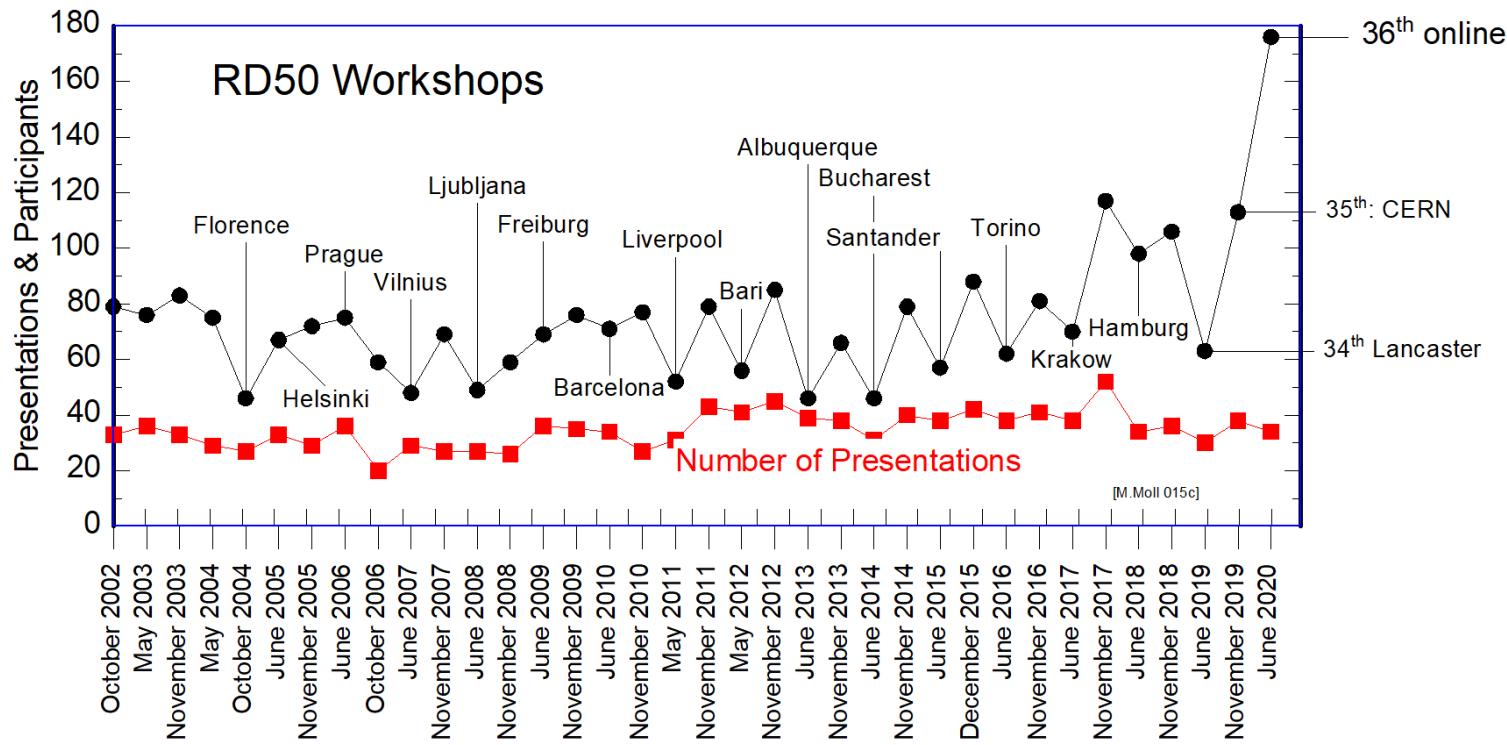
<https://cds.cern.ch/record/2320882/files/LHCC-SR-007.pdf>



RD50 Workshops

- June 2020 - CERN - online workshop

- Very high number of participants this time (176 registered); 34 talks + 4 discussions
- Average numbers for RD50 Workshops: <35 talks> <74 participants>



- Next workshops:

- November 2020: Zagreb, Croatia;
- June 2021: Valencia; November 2021: CERN; June 2022 Seville

Program: 36th Workshop



- Wednesday 3.6.2020
 - Defect, Material and Sensor Characterization (6 talks + discussion)
 - NIEL, Irradiation facilities, TCT results (8 talks)
 - *Collaboration Board (closed session)*
- Thursday 4.6.2020 [10:00 – 17:30]
 - Simulations: Radiation Damage – Signal Formation (3 talks + discussion)
 - LGAD – Low Gain Avalanche Detectors (10 talks + discussion)
- Friday 5.6.2020 [11:00 – 16:00]
 - 11:00 EP seminar “Innovative silicon sensors for future trackers”
by Nicolo Cartiglia, Marco Mandurrino
 - 13:00 CMOS sensors (6 talks + discussion)

Enjoy the Workshop!

...many thanks to

- the session chairs and discussion session leaders*
- the local organization team*

Anja, Esteban, Julian, Yana ...and especially to Veronique Wedlake!

